

Notice of References Cited	Application/Control No. 10/816,294	Applicant(s)/Patent Under Reexamination SEAGLE, DAVID J.	
	Examiner Tianjie Chen	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0252419 A1	12-2004	Takano, Kenichi	360/324.12
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NON-PATENT DOCUMENTS

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